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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors: Peter G. Borden; Ji-Ping Li
Title: Identifying Defects In A Conductive Structure Of A Wafer, Based On Heat Transfer Therethrough
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Santa Clara, California
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**INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR §1.97(d)**

Dear Sir:

Pursuant to 37 C.F.R. § 1.56, §1.97 and §1.98, the Applicants submit for consideration the attached International Search Report and Written Opinion (11 pages total) in a PCT application. The current application is cited in these papers by its publication number, i.e. US 2003/165178 A1. If a fee is required, please charge the deposit account 50-2263 and identify the charge by using the docket number BOX014 US.

The information contained in this Information Disclosure Statement is to the best of my knowledge and is not to be construed as a representation that: (i) a complete search has been made; (ii) additional information material to the examination of this application does not exist; (iii) the information, protocols, results and the like reported by third parties are accurate or enabling; or (iv) the above information constitutes prior art to the subject invention.

CERTIFICATE OF FACSIMILE TRANSMISSION

I hereby certify that this correspondence is being facsimile transmitted to the U.S. Patent and Trademark Office to the fax number 571-273-8300 on October 2, 2005.

S. Omkar *Oct 2, 2005*
Attorney for Applicant(s) Date of Signature

Respectfully submitted,

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